## Ordering Information

| $\mathrm{BV}_{\text {DSS }} /$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{BV}_{\mathrm{DGS}}$ |

${ }^{\dagger}$ MIL visual screening available

## High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process
Flows and Ordering Information.

## Features

- Free from secondary breakdown
- Low power drive requirement
- Ease of paralleling
- Low $\mathrm{C}_{\text {ISS }}$ and fast switching speeds
- Excellent thermal stability
- Integral Source-Drain diode
- High input impedance and high gain
- Complementary N - and P-channel devices


## Applications

- Motor controls
- Converters
- Amplifiers
- Switches
- Power supply circuits
- Drivers (relays, hammers, solenoids, lamps, memories, displays, bipolar transistors, etc.)

| Absolute Maximum Ratings |  |
| :--- | ---: |
| Drain-to-Source Voltage | $\mathrm{BV}_{\text {DSS }}$ |
| Drain-to-Gate Voltage | $\mathrm{BV}_{\text {DGS }}$ |
| Gate-to-Source Voltage | $\pm 20 \mathrm{~V}$ |
| Operating and Storage Temperature | $-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Soldering Temperature | $300^{\circ} \mathrm{C}$ |

* Distance of 1.6 mm from case for 10 seconds.


## Advanced DMOS Technology

These enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

## Package Options



## 05/19/03

## Thermal Characteristics

| Package | $\mathrm{I}_{\mathrm{D}}$ (continuous) | $\mathrm{I}_{\mathrm{D}}$ (pulsed) | Power Dissipation <br> $@ \mathbf{T}_{\mathbf{C}}=25^{\circ} \mathbf{C}$ | $\boldsymbol{\theta}_{\mathrm{jc}}$ <br> ${ }^{\circ} \mathbf{C} / \mathbf{W}$ | $\boldsymbol{\theta}_{\mathrm{ja}}$ <br> ${ }^{\circ} \mathbf{C} / \mathbf{W}$ | $\mathrm{I}_{\mathrm{DR}}{ }^{*}$ | $\mathrm{I}_{\mathrm{DRM}}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| TO-3 | -1.5 A | -3.0 A | 100 W | 1.25 | 30 | -1.5 A | -3.0 A |
| TO-220 | -1.0 A | -3.0 A | 50 W | 2.5 | 40 | -1.0 A | -3.0 A |

${ }^{*} I_{D}$ (continuous) is limited by max rated $T_{j}$.

Electrical Characteristics (@ $25^{\circ} \mathrm{C}$ unless otherwise specified)


Notes:

1. All D.C. parameters $100 \%$ tested at $25^{\circ} \mathrm{C}$ unless otherwise stated. (Pulse test: $300 \mu$ sulse, $2 \%$ duty cycle.)
2. All A.C. parameters sample tested.

## Switching Waveforms and Test Circuit




## Typical Performance Curves

Output Characteristics


Transconductance vs. Drain Current


Maximum Rated Safe Operating Area


Saturation Characteristics


Power Dissipation vs. Case Temperature


Thermal Response Characteristics


## Typical Performance Curves

$B V_{\text {DSS }}$ Variation with Temperature


Transfer Characteristics


Capacitance vs. Drain-to-Source Voltage


On-Resistance vs. Drain Current



Gate Drive Dynamic Characteristics


